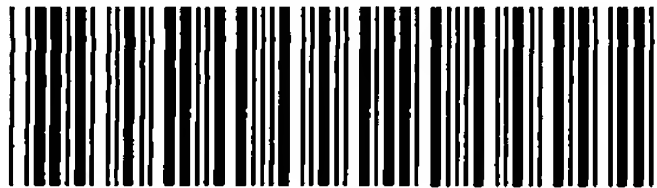


Search Notes

Application/Control No.

10/624,524

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST search and used previously cited references	5/16/2007	NT